IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ATTY.'S DOCKET: 98 P7501 US 01

In re the application of: Ramachandran et al.

Group Art: 1746

Serial No.: 09/204,706

Examiner: A. Olsen

Filing Date: December 3, 1998

Title: REMOVAL OF POST-RIE POLYMER)

ON Al/Cu METAL LINE

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents Box CPA Washington, D.C. 20231

Sir:

In advance of prosecution and before the application is taken up for examination on the merits, it is respectfully requested that the claims be amended as follows:

IN THE CLAIMS:

- 13. (Twice Amended) In a metal etch tool for removing post-RIE polymer rails formed on a Al/Cu metal line of a semiconductor structure, the improvement comprising an RECEIVED integrated metal etch tool comprising therein: [separate 00 0 5 2001
 - a) strip chamber means [for

TC 1700

forming a water-only plasma process] to strip the photoresist layer of a semiconductor composite structure with water

only plasma subsequent [previously subjected] to a RIE

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